Abstracts

Properties of Microstrip Lines on Fused Quartz (Correspondence)

J.H.C. van Heuven, A.G. van Nie and N.V. Phillips. "Properties of Microstrip Lines on Fused Quartz (Correspondence)." 1970 Transactions on Microwave Theory and Techniques 18.2 (Feb. 1970 [T-MTT]): 113-114.

The attenuation constant for microstrip lines on fused quartz and their effective relative dielectric constant were measured and the results are discussed. The propagation losses in these lines proved to be smaller than those mentioned in the literature. The effective relative dielectric constant is found to be independent of frequency up to 12 GHz. The conductors were deposited without an adhesive layer but with sufficient adhesion for pressure bonding semiconductor chips.

❑ Return to main document.